

## **Search Notes**



**Application/Control No.**

10/537,368

**Examiner**

Anh T.N. Vo

**Applicant(s)/Patent under  
Reexamination**

MURANAKA ET AL.

## **Art Unit**

2861

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner